AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings of claims in the application:

LISTING OF CLAIMS:

1 - 11 (Canceled)

- 12. (New) A system for manufacturing a fullerene derivative comprising means for generating high electron temperature plasma whose electron energy is kept 15 to 50 eV in order to generate a positive monovalent ion M⁺ from a gas containing an atom M which acts as a moiety in the production of a fullerene derivative; fullerene introducing means for introducing a fullerene into plasma comprised of M⁺ and electrons to produce a fullerene ion; and a deposition substrate where a fullerene derivative produced as a result of reaction between the fullerene ion and M⁺ is allowed to deposit.
- derivative comprising means for generating high electron temperature plasma whose electron energy is kept 15 to 50 eV in order to generate a positive monovalent ion M⁺ from a gas containing an atom M which acts as a moiety in the production of a fullerene derivative; fullerene introducing means for introducing a fullerene; and a deposition substrate, wherein plasma comprised of M⁺ is driven against the deposition substrate while at the same time fullerene ejected via the

fullerene introducing means is allowed to impinge onto the deposition substrate so that M^{\dagger} and fullerene react with each other to produce a fullerene derivative which deposits on the deposition substrate.

- 14. (New) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced.
- 15. (New) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced.
- 16. (New) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced, and a four phased helical antenna located between the pair of coils.
- 17. (New) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the

dispersion of positive ions produced, and a four phased helical antenna located between the pair of coils.

- 18. (New) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises gas introducing means, a microwave generator for exciting gas to produce positive ions therefrom, a pair of coils for generating a mirror field which prohibits dispersion of the positive ions produced, and a four phased helical antenna located between the pair of coils.
- 19. (New) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises gas introducing means, a microwave generator for exciting gas to produce positive ions therefrom, a pair of coils for generating a mirror field which prohibits dispersion of the positive ions produced, and a four phased helical antenna located between the pair of coils.
- 20. (New) The system as described in claim 12 for manufacturing a fullerene derivative further comprising electron energy control means for controlling the energy of electrons in a plasma to be in the range of 1 to 10 eV, the electron energy control means being located downstream of the high electron temperature plasma generating means in terms of the flow of plasma.

- 21. (New) The system as described in Claim 20 for manufacturing a fullerene derivative wherein the electron energy control means controls the energy of electrons by applying a control voltage to an electrode located upstream of the fullerene introducing means in terms of the flow of plasma.
- 22. (New) The system as described in Claim 12 for manufacturing a fullerene derivative.